

Abstracts

Novel method for calculation and measurement of unloaded Q-factor of superconducting dielectric resonators

M.V. Jacob, J. Mazierska, K. Leong and J. Krupka. "Novel method for calculation and measurement of unloaded Q-factor of superconducting dielectric resonators." 2001 MTT-S International Microwave Symposium Digest 01.3 (2001 Vol. III [MWSYM]): 1993-1996 vol.3.

The dielectric resonator technique is recognised as the best method for the measurement of surface resistance ($R_{\text{sub s}}$) of High Temperature Superconducting thin films. The $R_{\text{sub s}}$ is calculated from the Unloaded Q-factor ($Q_{\text{sub 0}}$) of the resonator, and to obtain accurate values of the $Q_{\text{sub 0}}$ -factor multi-frequency measurements of $S_{\text{sub 21}}$, $S_{\text{sub 11}}$ and $S_{\text{sub 22}}$ and data circle fitting are required. As a result, surface resistance measurements at varying temperatures are very time consuming. In this paper we introduce a simplified method for calculations the $Q_{\text{sub 0}}$ -factor, which require measurements of $S_{\text{sub 11}}$ and $S_{\text{sub 22}}$ at the lowest temperature only. For all other temperatures only $S_{\text{sub 21}}$ measurements are needed. The method has shown to give sufficiently accurate $Q_{\text{sub 0}}$ values and hence the surface resistance.

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